PSMN038-100K

N-channel TrenchMOS SiliconMAX standard level FET

Rev. 02 — 25 November 2009

Product data sheet

1. Product profile

1.1 General description

SiliconMAX standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Suitable for high frequency applications due to fast switching characteristics

1.3 Applications

- Computer motherboards
- DC-to-DC convertors

Switched-mode power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	-	100	V
I _D	drain current	$T_{sp} = 80 \text{ °C};$ see <u>Figure 1</u> and <u>3</u>	-	-	6.3	Α
P _{tot}	total power dissipation	T _{sp} = 80 °C; see <u>Figure 2</u>	-	-	3.5	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; I_D = 6.3 \text{ A};$ $V_{DS} = 50 \text{ V}; T_j = 25 \text{ °C};$ see Figure 11	-	16	21.5	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 5.2 \text{ A};$ $T_j = 25 \text{ °C};$ see Figure 9 and 10	-	33	38	mΩ



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source	8	D
3	S	source		G (F)
4	G	gate		
5	D	drain	1 1 1 1 14	mbb076 S
6	D	drain	SOT96-1 (SO8)	
7	D	drain		
8	D	drain		

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PSMN038-100K	SO8	plastic small outline package; 8 leads; body width 3.9 mm	SOT96-1

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	100	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	$T_{sp} = 80 ^{\circ}\text{C}$; see Figure 1 and 3	-	6.3	Α
I_{DM}	peak drain current	T_{sp} = 25 °C; $t_p \le 10 \mu s$; pulsed; see Figure 3	-	50	Α
P _{tot}	total power dissipation	T _{sp} = 80 °C; see <u>Figure 2</u>	-	3.5	W
T _{stg}	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-dra	ain diode				
Is	source current	$T_{sp} = 80 ^{\circ}C$	-	3.1	Α
I _{SM}	peak source current	T_{sp} = 25 °C; $t_p \le 10 \mu s$; pulsed	-	50	Α

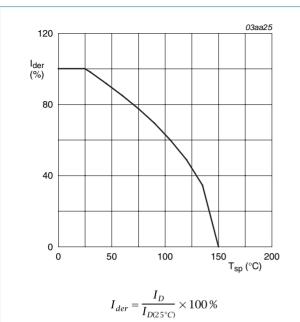


Fig 1. Normalized continuous drain current as a function of solder point temperature

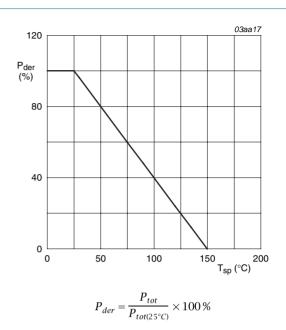
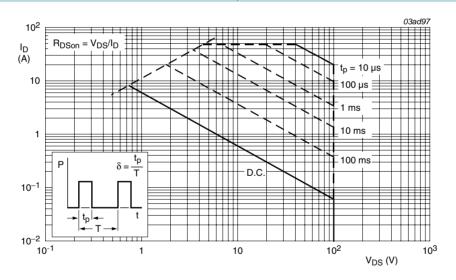


Fig 2. Normalized total power dissipation as a function of solder point temperature



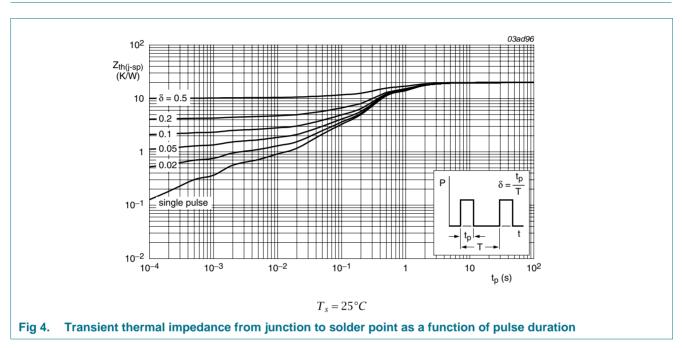
 $T_{sp} = 25$ °C; I_{DM} is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 5. Thermal characteristics

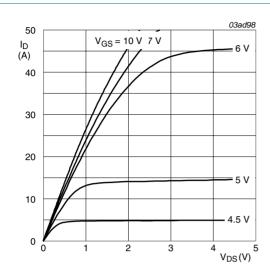
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-sp)}$	thermal resistance from junction to solder point	mounted on a metal clad substrate;see Figure 4	-	-	20	K/W



Characteristics

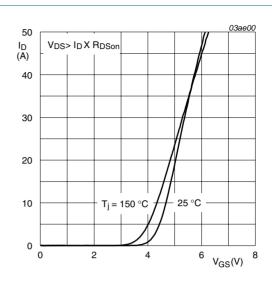
Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	100	130	-	V
$V_{GS(th)}$	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 150 °C; see <u>Figure 8</u>	1.2	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see <u>Figure 8</u>	-	-	6	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see Figure 8	2	-	4	V
I _{DSS}	drain leakage current	$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 ^{\circ}\text{C}$	-	-	0.5	mΑ
		$V_{DS} = 80 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	-	1	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	-	100	nA
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
DOON	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 5.2 \text{ A}; T_j = 150 ^{\circ}\text{C};$ see Figure 9 and 10	-	76	88	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 5.2 \text{ A}; T_j = 25 \text{ °C};$ see Figure 9 and 10	-	33	38	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 6.3 \text{ A}$; $V_{DS} = 50 \text{ V}$; $V_{GS} = 10 \text{ V}$;	-	43	-	nC
Q_{GS}	gate-source charge	$T_j = 25 ^{\circ}\text{C}$; see Figure 11	-	6.5	-	nC
Q_{GD}	gate-drain charge		-	16	21.5	nC
C _{iss}	input capacitance	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	1740	-	pF
C _{oss}	output capacitance	$T_j = 25$ °C; see Figure 12	-	220	-	pF
C _{rss}	reverse transfer capacitance		-	135	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 50 \text{ V}; R_L = 50 \Omega; V_{GS} = 10 \text{ V};$	-	15	30	ns
t _r	rise time	$R_{G(ext)} = 6 \Omega; T_j = 25 \text{ °C}; I_D = 1 \text{ A}$	-	13	25	ns
t _{d(off)}	turn-off delay time		-	50	80	ns
t _f	fall time		-	25	40	ns
9 _{fs}	transfer conductance	$V_{DS} = 15 \text{ V}; I_D = 6.3 \text{ A}; \text{ see } \frac{\text{Figure } 13}{\text{ Figure } 13}$	-	20	-	S
Source-di	rain diode					
V_{SD}	source-drain voltage	$I_S = 2.3 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 14</u>	-	0.7	1.1	V
t _{rr}	reverse recovery time	$I_S = 6.3 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	85	-	ns
Qr	recovered charge	$V_{DS} = 25 \text{ V}; T_j = 25 \text{ °C}$	-	0.3	-	μC



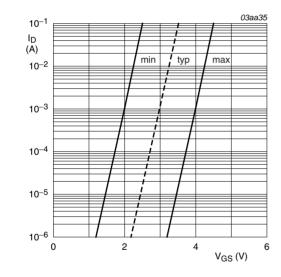
 $T_i = 25^{\circ}C$

Output characteristics: drain current as a Fig 5. function of drain-source voltage; typical values



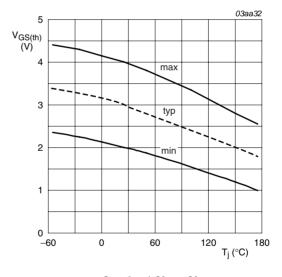
$$T_j = 25$$
° C and 150 ° C ; $V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values



 $T_i = 25 \,^{\circ}C; V_{DS} = 5V$

Sub-threshold drain current as a function of gate-source voltage



 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 8. Gate-source threshold voltage as a function of junction temperature

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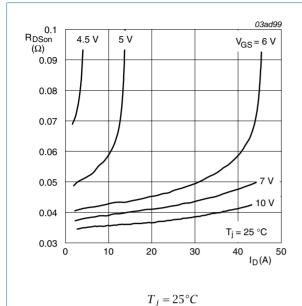


Fig 9. Drain-source on-state resistance as a function of drain current; typical values

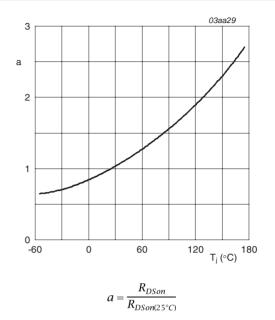
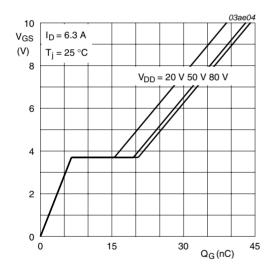
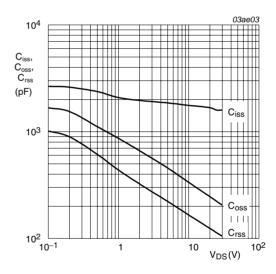


Fig 10. Normalized drain-source on-state resistance factor as a function of junction temperature



 $I_D = 6.3A$; $V_{DS} = 20V$, 50V and 80V

Fig 11. Gate-source voltage as a function of gate charge; typical values



$$V_{GS} = 0V; f = 1MHz$$

Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

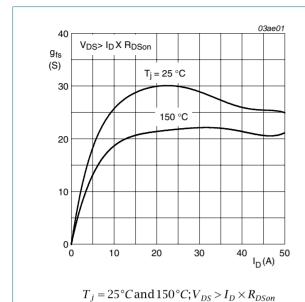


Fig 13. Forward transconductance as a function of drain current; typical values

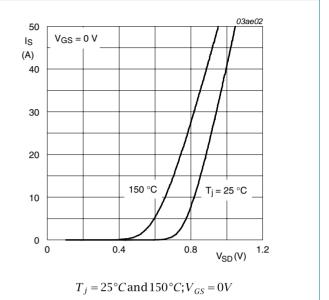
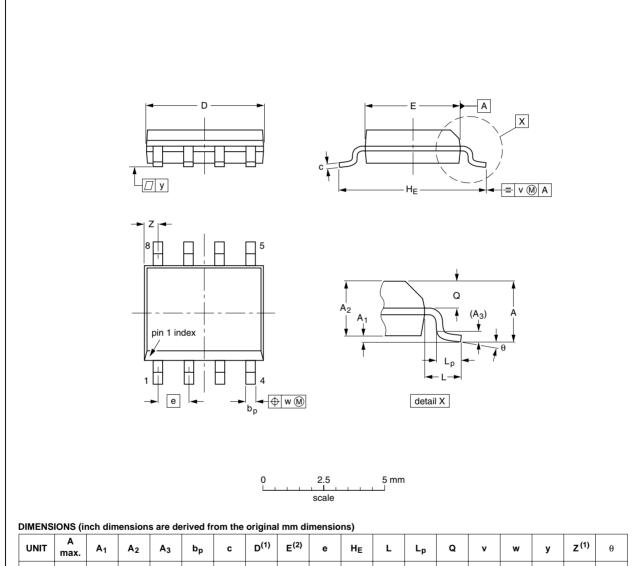


Fig 14. Source current as a function of source-drain voltage; typical values

7. Package outline

SO8: plastic small outline package; 8 leads; body width 3.9 mm

SOT96-1



UNIT	A max.	A ₁	A ₂	A ₃	bp	С	D ⁽¹⁾	E ⁽²⁾	е	HE	L	Lp	Q	v	w	у	z ⁽¹⁾	θ
mm	1.75	0.25 0.10	1.45 1.25	0.25	0.49 0.36	0.25 0.19	5.0 4.8	4.0 3.8	1.27	6.2 5.8	1.05	1.0 0.4	0.7 0.6	0.25	0.25	0.1	0.7 0.3	8°
inches	0.069	0.010 0.004	0.057 0.049	0.01		0.0100 0.0075	0.20 0.19	0.16 0.15	0.05	0.244 0.228	0.041	0.039 0.016		0.01	0.01	0.004	0.028 0.012	0°

Notes

- 1. Plastic or metal protrusions of 0.15 mm (0.006 inch) maximum per side are not included.
- 2. Plastic or metal protrusions of 0.25 mm (0.01 inch) maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	
SOT96-1	076E03	MS-012			99-12-27 03-02-18

Fig 15. Package outline SOT96-1 (SO8)

PSMN038-100K_2

8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes				
PSMN038-100K_2	20091125	Product data sheet	-	PSMN038-100K-01				
Modifications:		 The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. 						
 Legal texts have been adapted to the new company name where appropriate. 								
PSMN038-100K-01	20010116	Product specification	-	-				

9. Legal information

9.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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